

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination OKAMURA ET AL.	
		Examiner NARAYAN K. BHAT	Art Unit 1634	Page 1 of 1

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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-5,929,194	07-1999	Woo et al.	528/229
B	US-			
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D	US-			
E	US-			
F	US-			
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I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

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N	WO 03/020425	03-2003	USA	Mao et al	
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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	Langer et al, Thermal conductivity of thin metallic films measured by photothermal profile analysis, 1997, Rev. Sci. Instrum. 68, 1510-1513.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.